

<b>Notice of References Cited</b>	Application/Control No. 10/059,173	Applicant(s)/Patent Under Reexamination HAN ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,594,313 B1	07-2003	Hazra et al.	375/240.16
	B	US-5,546,130 A	08-1996	Hackett et al.	348/447
	C	US-6,438,170 B1	08-2002	Hackett et al.	375/240.16
	D	US-6,285,711 B1	09-2001	Ratakonda et al.	375/240.16
	E	US-2002/0131502 A1	09-2002	Monro et al.	375/240.16
	F	US-2002/0025077 A1	02-2002	DE HAAN et al.	382/238
	G	US-6,430,223 B1	08-2002	Lim, Kyoung Won	375/240.16
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

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